

Notice of References Cited	Application/Control No. 10/809,130		Applicant(s)/Patent Under Reexamination SEO ET AL.	
	Examiner C. Melissa Koslow		Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	K	US-			
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	U	Liang et al, "ICP-AES Detection of Ultratrace Aluminum(iii) and Chromium(III) Ions with a Microcolumn Preconcentration System Using Dynamically Immobilized 8-Hydroxyquinoline on TiO2 Nanoperatyicles", Ana Sci, 8/2003, Vol. 19, pp. 1167-1171.
	V	Takaeda et al, "Modification of sol-gel-derived amorphous Al2O3 thin films by F2 excimer laser irradiation at ambient temperature", J. Mater. Res., Vol 16, No. 4, 4/2001, pp.1003-1009.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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